

REVISIONS			
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
A	Update drawing to current requirements. Editorial changes throughout. - gap	01-05-16	Raymond Monnin
B	Boilerplate update and part of five year review. tcr	06-04-27	Raymond Monnin
C	Update drawing to the current requirements of MIL-PRF-38535. - glg	14-08-11	Charles Saffle



REV																				
SHEET																				
REV	C	C	C	C	C	C	C	C	C											
SHEET	15	16	17	18	19	20	21	22	23											
REV STATUS OF SHEETS	REV			C	C	C	C	C	C	C	C	C	C	C	C	C	C	C	C	C
	SHEET			1	2	3	4	5	6	7	8	9	10	11	12	13	14			
PMIC N/A	PREPARED BY Jeff Bowling									<p align="center"><b>DLA LAND AND MARITIME</b>  <b>COLUMBUS, OHIO 43218-3990</b>  <a href="http://www.landandmaritime.dla.mil">http://www.landandmaritime.dla.mil</a></p> <p><b>MICROCIRCUIT, MEMORY, DIGITAL, 8K X 8 NONVOLATILE STATIC RAM WITH AUTOMATIC STORE ON POWER LOSS, MONOLITHIC SILICON</b></p>										
<p align="center"><b>STANDARD MICROCIRCUIT DRAWING</b></p> <p align="center">THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE</p> <p align="center">AMSC N/A</p>	CHECKED BY Jeff Bowling																			
	APPROVED BY Michael A. Frye																			
	DRAWING APPROVAL DATE 94-08-12																			
	REVISION LEVEL C									SIZE A	CAGE CODE 67268	<b>5962-94599</b>								
										SHEET 1 OF 23										



1.3 Absolute maximum ratings. 1/ 2/

Supply voltage range (V <sub>CC</sub> ).....	-0.6 V dc to 7.0 V dc
Voltage on DQ <sub>(0-7)</sub> with outputs in high Z state .....	-0.5 V to (V <sub>CC</sub> +0.5 V)
Input voltage operating range (V <sub>IH</sub> , V <sub>IL</sub> ) .....	-0.6 V dc to 7.0 V dc
Storage temperature range.....	-65°C to +150°C
Maximum power dissipation (P <sub>D</sub> ).....	1.0 W
Maximum output current.....	15 mA
Lead temperature (soldering) .....	300°C
Junction temperature (T <sub>J</sub> ) 3/ .....	175°C
Thermal resistance, junction to case (θ <sub>JC</sub> ) .....	See MIL-STD-1835
Data retention.....	10 years to nonvolatile array (minimum)
Endurance (as store cycles to non-volatile array).....	100,000 store cycles (minimum)

1.4 Recommended operating conditions. 1/ 2/

Supply voltage range (V <sub>CC</sub> ).....	+4.5 V dc to +5.5 V dc
Case operating temperature range (T <sub>C</sub> ).....	-55°C to +125°C
Input voltage, low range (V <sub>IL</sub> ).....	V <sub>SS</sub> -0.5 V dc to 0.8 V dc, all inputs
Input voltage, high range (V <sub>IH</sub> ).....	2.2 V dc to V <sub>CC</sub> +0.5 V dc, all inputs

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits.  
 MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.  
 MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at <http://quicksearch.dla.mil> or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Non-Government publications. The following documents form a part of this document to the extent specified herein. Unless otherwise specified, the issues of the documents are the issues of the documents cited in the solicitation.

JEDEC – SOLID STATE TECHNOLOGY ASSOCIATION (JEDEC)

JEDEC Standard JESD78 - IC Latch-Up Test.

(Copies of this document are available online at [www.jedec.org](http://www.jedec.org) or from JEDEC – Solid State Technology Association, 3103 North 10<sup>th</sup> Street, Suite 247, Arlington, VA 22201).

(Non-Government standards and other publications are normally available from the organizations that prepare or distribute the documents. These documents also may be available in or through libraries or other informational services.)

- 1/ Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.  
 2/ All voltages are referenced to V<sub>SS</sub> (ground).  
 3/ Maximum junction temperature shall not be exceeded except for allowable short duration burn-in screening conditions in accordance with method 5004 of MIL-STD-883.

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2.3 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements for device classes Q and V shall be in accordance with MIL-PRF-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. The individual item requirements for device class M shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein for device classes Q and V or MIL-PRF-38535, appendix A and herein for device class M.

3.2.1 Case outlines. The case outlines shall be in accordance with 1.2.4 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.3 Truth table. The truth table shall be as specified on figure 2.

3.2.4 Functional tests. Various functional tests used to test this device are contained in the appendix. If the test patterns cannot be implemented due to test equipment limitations, alternate test patterns to accomplish the same results shall be allowed. For device class M, alternate test patterns shall be maintained under document revision level control by the manufacturer and shall be made available to the preparing or acquiring activity upon request. For device classes Q and V alternate test patterns shall be under the control of the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the preparing or acquiring activity upon request.

3.3 Electrical performance characteristics and postirradiation parameter limits. Unless otherwise specified herein, the electrical performance characteristics and postirradiation parameter limits are as specified in table I and shall apply over the full case operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table IIA. The electrical tests for each subgroup are defined in table I.

3.5 Marking. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked. For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device. For RHA product using this option, the RHA designator shall still be marked. Marking for device classes Q and V shall be in accordance with MIL-PRF-38535. Marking for device class M shall be in accordance with MIL-PRF-38535, appendix A.

3.5.1 Certification/compliance mark. The certification mark for device classes Q and V shall be a "QML" or "Q" as required in MIL-PRF-38535. The compliance mark for device class M shall be a "C" as required in MIL-PRF-38535, appendix A.

3.6 Certificate of compliance. For device classes Q and V, a certificate of compliance shall be required from a QML-38535 listed manufacturer in order to supply to the requirements of this drawing (see 6.6.1 herein). For device class M, a certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6.2 herein). The certificate of compliance submitted to DLA Land and Maritime-VA prior to listing as an approved source of supply for this drawing shall affirm that the manufacturer's product meets, for device classes Q and V, the requirements of MIL-PRF-38535 and herein or for device class M, the requirements of MIL-PRF-38535, appendix A and herein.

3.7 Certificate of conformance. A certificate of conformance as required for device classes Q and V in MIL-PRF-38535 or for device class M in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change for device class M. For device class M, notification to DLA Land and Maritime-VA of change of product (see 6.2 herein) involving devices acquired to this drawing is required for any change that affects this drawing.

3.9 Verification and review for device class M. For device class M, DLA Land and Maritime, DLA Land and Maritime's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

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3.10 Microcircuit group assignment for device class M. Device class M devices covered by this drawing shall be in microcircuit group number 41 (see MIL-PRF-38535, appendix A).

3.11 Endurance. A reprogrammability test shall be completed as part of the vendor's reliability monitors. This reprogrammability test shall be done for initial characterization and after any design or process changes which may affect the reprogrammability of the device. The methods and procedures may be vendor specific, but shall guarantee the number of program/erase endurance cycles listed in section 1.3 herein over the full military temperature range. The vendor's procedure shall be kept under document control and shall be made available upon request of the acquiring or preparing activity, along with test data.

3.12 Data retention. A data retention stress test shall be completed as part of the vendor's reliability monitors. This test shall be done for initial characterization and after any design or process changes which may affect data retention. The methods and procedures may be vendor specific, but shall guarantee the number of years listed in section 1.3 herein over the full military temperature range. The vendor's procedure shall be kept under document control and shall be made available upon request of the acquiring or preparing activity, along with test data.

#### 4. VERIFICATION

4.1 Sampling and inspection. For device classes Q and V, sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. For device class M, sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. For device classes Q and V, screening shall be in accordance with MIL-PRF-38535, and shall be conducted on all devices prior to qualification and technology conformance inspection. For device class M, screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection.

##### 4.2.1 Additional criteria for device class M.

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015.

(2)  $T_A = +125^\circ\text{C}$ , minimum.

b. Interim and final electrical test parameters shall be as specified in table IIA herein.

##### 4.2.2 Additional criteria for device classes Q and V.

a. The burn-in test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document revision level control of the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.

b. Interim and final electrical test parameters shall be as specified in table IIA herein.

c. Additional screening for device class V beyond the requirements of device class Q shall be as specified in MIL-PRF-38535, appendix B.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C ≤ T <sub>C</sub> ≤ +125°C 4.5 V ≤ V <sub>CC</sub> ≤ 5.5 V V <sub>SS</sub> = 0 V, I <sub>OUT</sub> = 0 mA unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
V <sub>CC</sub> current <u>1/</u>	I <sub>CC1</sub>	Addresses cycling at t <sub>AVAV</sub>	1, 2, 3	01		75	mA
				02		80	
				03		85	
V <sub>CC</sub> current during store cycle	I <sub>CC2</sub>	All inputs ≤ 0.2 V or ≥ V <sub>CC</sub> - 0.2 V	1, 2, 3	All		8	mA
V <sub>CC</sub> current at t <sub>AVAV</sub> = 200 ns <u>1/</u>	I <sub>CC3</sub>	All inputs ≤ 0.2 V or ≥ V <sub>CC</sub> - 0.2 V	1, 2, 3	All		15	mA
V <sub>CC</sub> current during automatic store on power loss	I <sub>CC4</sub>	$\overline{CE} \geq V_{CC}-0.2 V$ ; all others V <sub>IN</sub> ≤ 0.2 V or ≥ V <sub>CC</sub> -0.2 V	1, 2, 3	All		4	mA
V <sub>CC</sub> current (standby, cycling TTL input levels) <u>2/</u>	I <sub>CC5</sub>	$\overline{CE} \geq V_{IH}$ ; all others cycling	1, 2, 3	01		28	mA
				02		32	
				03		35	
V <sub>CC</sub> DC current (standby, stable CMOS input levels) <u>2/</u>	I <sub>CC6</sub>	$\overline{CE} \geq V_{CC}-0.2 V$ ; all others V <sub>IN</sub> ≤ 0.2 V or ≥ V <sub>CC</sub> -0.2 V	1, 2, 3	All		4	mA
Input leakage current (any input)	I <sub>ILK</sub>	V <sub>CC</sub> = 5.5 V V <sub>IN</sub> = V <sub>SS</sub> to V <sub>CC</sub>	1, 2, 3	All		±1	μA
Off state output leakage current	I <sub>OLK</sub>	V <sub>CC</sub> = 5.5 V V <sub>IN</sub> = V <sub>SS</sub> to V <sub>CC</sub>	1, 2, 3	All		±5	μA
Input logic "1" voltage	V <sub>IH</sub>	All Inputs	1, 2, 3	All	2.2	V <sub>CC</sub> + .5	V
Input logic "0" voltage	V <sub>IL</sub>	All Inputs	1, 2, 3	All	V <sub>SS</sub> - .5	0.8	V
Output Logic "1" voltage	V <sub>OH</sub>	I <sub>OH</sub> = -4mA <u>3/</u>	1, 2, 3	All	2.4		V
Output Logic "0" voltage	V <sub>OL</sub>	I <sub>OL</sub> = 8mA <u>3/</u>	1, 2, 3	All		0.4	V
Input capacitance <u>4/</u>	C <sub>IN</sub>	ΔV = 0 to 3 V T <sub>A</sub> = 25°C, f = 1.0 MHz See 4.4.1e	4	All		8	pF
Output capacitance <u>4/</u>	C <sub>OUT</sub>	ΔV = 0 to 3 V T <sub>A</sub> = 25°C, f = 1.0 MHz See 4.4.1e	4	All		7	pF

See footnotes at end of table.

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TABLE I. Electrical performance characteristics- Continued.

Test	Symbol	Conditions -55°C ≤ T <sub>C</sub> ≤ +125°C 4.5 V ≤ V <sub>CC</sub> ≤ 5.5 V V <sub>SS</sub> = 0 V, I <sub>OUT</sub> = 0 mA unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Functional tests		See 4.4.1c	7, 8A, 8B				
READ CYCLES #1 & #2							
Chip enable access time	t <sub>ELQV</sub>	See figures 3 and 4	9, 10, 11	01		55	ns
				02		45	
				03		35	
Read cycle time	t <sub>AVAV</sub>		9, 10, 11	01	55		ns
				02	45		
				03	35		
Address access time <u>5/</u>	t <sub>AVQV</sub>		9, 10, 11	01		55	ns
				02		45	
				03		35	
Output enable to data valid	t <sub>OLQV</sub>		9, 10, 11	01		35	ns
				02		25	
				03		20	
Output hold after address change	t <sub>AXQX</sub>		9, 10, 11	All	5		ns
Chip enable to output active	t <sub>ELQX</sub>		9, 10, 11	All	5		ns
Chip disable to output inactive <u>6/</u>	t <sub>EHQZ</sub>	9, 10, 11	01		25	ns	
			02		20		
			03		17		
Output enable to output active	t <sub>OLQX</sub>	9, 10, 11	All	0		ns	
Output disable to output inactive <u>6/</u>	t <sub>OHQZ</sub>	9, 10, 11	01		25	ns	
			02		20		
			03		17		
Chip enable to power active <u>4/</u>	t <sub>ELPU</sub>	9, 10, 11	All	0		ns	
Chip disable to power standby <u>2/ 4/</u>	t <sub>EHPD</sub>	9, 10, 11	01		55	ns	
			02		45		
			03		35		

See footnotes at end of table.

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TABLE I. Electrical performance characteristics- Continued.

Test	Symbol	Conditions -55°C ≤ T <sub>C</sub> ≤ +125°C 4.5 V ≤ V <sub>CC</sub> ≤ 5.5 V V <sub>SS</sub> = 0 V, I <sub>OUT</sub> = 0 mA unless otherwise specified	Group A subgroups	Device type	Limits		Unit			
					Min	Max				
WRITE CYCLE #1										
Write cycle time	t <sub>AVAV</sub>	See figures 3 and 4	9, 10, 11	01	55		ns			
				02	45					
				03	35					
Write pulse width	t <sub>WLWH</sub>		See figures 3 and 4	9, 10, 11	01	45		ns		
					02	35				
					03	30				
Chip enable to end of write	t <sub>ELWH</sub>			See figures 3 and 4	9, 10, 11	01	45		ns	
						02	35			
						03	30			
Data set-up to end of write	t <sub>DVWH</sub>				See figures 3 and 4	9, 10, 11	01	25		ns
							02	20		
		03					18			
Data hold after end of write	t <sub>WHDX</sub>	See figures 3 and 4				9, 10, 11	All	0		ns
Address set-up to end of write	t <sub>AVWH</sub>					9, 10, 11	01	45		ns
			02				35			
			03				30			
Address set-up to start of write	t <sub>AVWL</sub>		See figures 3 and 4			9, 10, 11	All	0		ns
Address hold after end of write	t <sub>WHAX</sub>			9, 10, 11		All	0		ns	
Write enable to output disable <u>6/ 7/</u>	t <sub>WLQZ</sub>			9, 10, 11		01		25	ns	
						02		20		
					03		17			
Output active after end of write	t <sub>WHQX</sub>			See figures 3 and 4	9, 10, 11	All	5		ns	
WRITE CYCLE #2										
Write cycle time	t <sub>AVAV</sub>	See figures 3 and 4			9, 10, 11	01	55		ns	
						02	45			
						03	35			
Write pulse width	t <sub>WLEH</sub>				See figures 3 and 4	9, 10, 11	01	45		ns
			02				35			
			03				30			

See footnotes at end of table.

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TABLE I. Electrical performance characteristics- Continued.

Test	Symbol	Conditions -55°C ≤ T <sub>C</sub> ≤ +125°C 4.5 V ≤ V <sub>CC</sub> ≤ 5.5 V V <sub>SS</sub> = 0 V, I <sub>OUT</sub> = 0 mA unless otherwise specified	Group A subgroups	Device type	Limits		Unit					
					Min	Max						
Chip enable to end of write	t <sub>ELEH</sub>	See figures 3 and 4	9, 10, 11	01	45		ns					
				02	35							
				03	30							
Data set-up to end of write	t <sub>DVEH</sub>			9, 10, 11	01			25		ns		
					02			20				
					03			18				
Data hold after end of write	t <sub>EHDx</sub>			9, 10, 11	All			0		ns		
Address set-up to end of write	t <sub>AVEH</sub>	9, 10, 11	01	45		ns						
			02	35								
			03	30								
Address set-up to start of write	t <sub>AVEL</sub>	9, 10, 11	All	0		ns						
Address hold after end of write	t <sub>EHAX</sub>	9, 10, 11	All	0		ns						
<b>HARDWARE STORE/RECALL</b>												
RECALL cycle duration	t <sub>RECALL</sub>	See figures 3 and 4	9, 10, 11	All		25	μs					
STORE cycle duration	t <sub>STORE</sub>	V <sub>CC</sub> ≥ 4.5 V. See figures 3 and 4	9, 10, 11	All		12	ms					
Power down STORE duration	t <sub>PDStore</sub>	See figures 3 and 4	9, 10, 11	All		12	ms					
HSB low to inhibit on	t <sub>DELAY</sub>							9, 10, 11	All	1		μs
HSB high to inhibit off	t <sub>RECOVER</sub>							9, 10, 11	All		300	ns
External STORE pulse width 4/	t <sub>ASSERT</sub>							9, 10, 11	All	250		ns
Low voltage trigger level	V <sub>SWITCH</sub>							9, 10, 11	All	4.0	4.5	V
HSB output low current 3/ 4/	I <sub>HSB_OL</sub>							9, 10, 11	All	3		mA

See footnotes at end of table.

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TABLE I. Electrical performance characteristics- Continued.

Test	Symbol	Conditions -55°C ≤ T <sub>C</sub> ≤ +125°C 4.5 V ≤ V <sub>CC</sub> ≤ 5.5 V V <sub>SS</sub> = 0 V, I <sub>OUT</sub> = 0 mA unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
$\overline{\text{HSB}}$ output high current 3/ 4/	I <sub>HSB_OH</sub>		9, 10, 11	All	5	60	μA
STORE/RECALL initiation cycle time	t <sub>AVAVN</sub>	See figures 3 and 4	9, 10, 11	01	55		ns
				02	45		
				03	35		
Chip enable to output 8/ inactive	t <sub>ELQZ</sub>		9, 10, 11	All		85	ns
Address set-up to chip enable	t <sub>AVELN</sub>		9, 10, 11	All	0		ns
Chip enable pulse width 9/ 10/	t <sub>ELEHN</sub>		9, 10, 11	01	45		ns
				02	35		
		03		25			
Chip disable to address change	t <sub>EHAXN</sub>	9, 10, 11	All	0		ns	

- 1/ I<sub>CC1</sub> and I<sub>CC3</sub> are dependent on output loading and cycle rate. The specified values are obtained with outputs unloaded.
- 2/ Bringing  $\overline{\text{CE}} \geq V_{IH}$  will not produce standby current levels until any nonvolatile cycle in progress has timed out. See Figure 2, Truth Table.
- 3/  $\overline{\text{HSB}}$  is an I/O that has a weak internal pull-up. It functions as an open drain output. It is designed to allow up to 32 8K x 8 NVSRAM with automatic store on power loss devices to be grouped together for simultaneous storing. This function may not be used for any purpose than that stated in this note.  $\overline{\text{HSB}}$  is specified separately for I<sub>OL</sub> and is unspecified for I<sub>OH</sub>.
- 4/ These parameters are tested as part of initial device characterization, and after any design or process change that might affect that parameter. These parameters are not tested as part of lot by lot screening, but are guaranteed to the limits specified in Table I.
- 5/ The device is continuously selected with  $\overline{\text{CE}}$  low and  $\overline{\text{OE}}$  low.
- 6/ Measured ±200 mV from steady state output voltage.
- 7/ If  $\overline{\text{WE}}$  is low when  $\overline{\text{CE}}$  goes low, the outputs remain in the high impedance state.
- 8/ Once the software STORE or RECALL cycle is initiated, it completes automatically, ignoring all inputs.
- 9/ Noise on the  $\overline{\text{CE}}$  pin may trigger multiple read cycles from the same address and abort the address sequence.
- 10/ If the Chip enable pulse width is less than t<sub>ELQV</sub> (see READ CYCLE #2) but greater than or equal to t<sub>ELEHN</sub>, then the data may not be valid at the end of the low pulse; however, the STORE or RECALL will still be initiated.

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Device types	ALL
Case outlines	X, Y
Terminal number	Terminal symbol
1	V <sub>CAP</sub>
2	A <sub>12</sub>
3	A <sub>7</sub>
4	A <sub>6</sub>
5	A <sub>5</sub>
6	A <sub>4</sub>
7	A <sub>3</sub>
8	A <sub>2</sub>
9	A <sub>1</sub>
10	A <sub>0</sub>
11	DQ <sub>0</sub>
12	DQ <sub>1</sub>
13	DQ <sub>2</sub>
14	V <sub>SS</sub>
15	DQ <sub>3</sub>
16	DQ <sub>4</sub>
17	DQ <sub>5</sub>
18	DQ <sub>6</sub>
19	DQ <sub>7</sub>
20	$\overline{\text{CE}}$
21	A <sub>10</sub>
22	$\overline{\text{OE}}$
23	A <sub>11</sub>
24	A <sub>9</sub>
25	A <sub>8</sub>
26	$\overline{\text{HSB}}$
27	$\overline{\text{WE}}$
28	V <sub>CC</sub>

FIGURE 1. Terminal connections.

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$\overline{CE}$	$\overline{WE}$	$\overline{HSB}$	A <sub>12</sub> -A <sub>0</sub> (HEX)	MODE	I/O	POWER	NOTES
H	X	H	X	Not Selected	Output High Z	Standby	
L	H	H	X	Read RAM	Output Data	Active	<u>2/</u>
L	L	H	X	Write RAM	Input Data	Active	
L	H	H	0000	Read SRAM	Output Data	Active	<u>1/</u> <u>2/</u>
			1555	Read SRAM	Output Data		<u>1/</u> <u>2/</u>
			0AAA	Read SRAM	Output Data		<u>1/</u> <u>2/</u>
			1FFF	Read SRAM	Output Data		<u>1/</u> <u>2/</u>
			1010	Read SRAM	Output Data		<u>1/</u> <u>2/</u>
			0F0F	Nonvolatile STORE	Output High Z		<u>2/</u>
L	H	H	0000	Read SRAM	Output Data	Active	<u>1/</u> <u>2/</u>
			1555	Read SRAM	Output Data		<u>1/</u> <u>2/</u>
			0AAA	Read SRAM	Output Data		<u>1/</u> <u>2/</u>
			1FFF	Read SRAM	Output Data		<u>1/</u> <u>2/</u>
			10F0	Read SRAM	Output Data		<u>1/</u> <u>2/</u>
			0F0E	Nonvolatile RECALL	Output High Z		<u>2/</u>
X	X	L	X	STORE/Inhibit	Output High Z	I <sub>CC2</sub> / Standby	<u>3/</u>

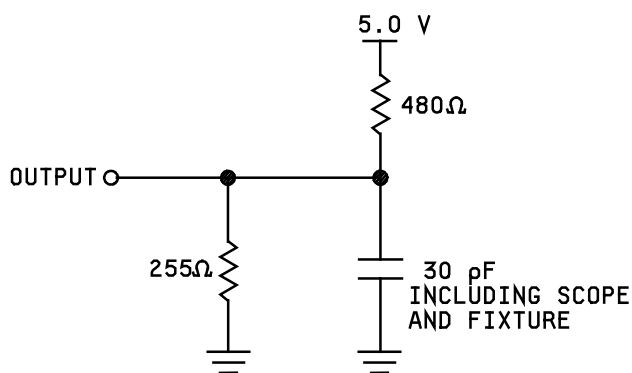
1/ The six consecutive addresses must be in order listed - (0000, 1555, 0AAA, 1FFF, 10F0, 0F0F) for a STORE cycle or (0000, 1555, 0AAA, 1FFF, 10F0, 0F0E) for a RECALL cycle.  $\overline{WE}$  must be high during all six consecutive cycles. See STORE cycle and RECALL cycle tables and diagrams for further details.

2/ I/O state assumes that  $\overline{OE} \leq V_{IL}$ . Activation of nonvolatile cycles does not depend on the state of  $\overline{OE}$ .

3/  $\overline{HSB}$  initiated STORE operation actually occurs only if a WRITE has been done since last STORE operation. After the STORE (if any) completes, the part will go into standby mode inhibiting all operation until  $\overline{HSB}$  rises.

FIGURE 2. Truth table.

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AC TEST CONDITIONS <sup>1/</sup>

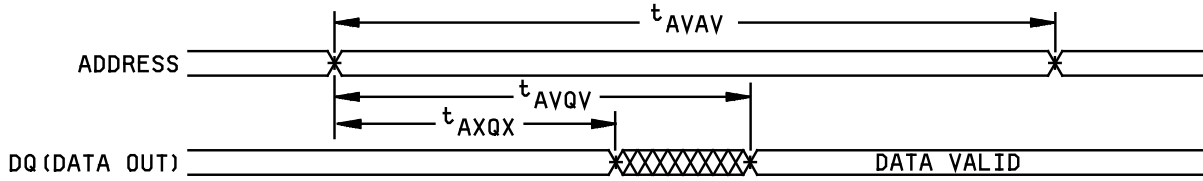
TEST CONDITION	VALUES
Input pulse levels	V <sub>SS</sub> to 3 V
Input rise & fall time	≤ 5 ns
Input and output timing reference levels	1.5 V
Output load	Per Figure 3

<sup>1/</sup> All voltages are referenced to V<sub>SS</sub> (ground).

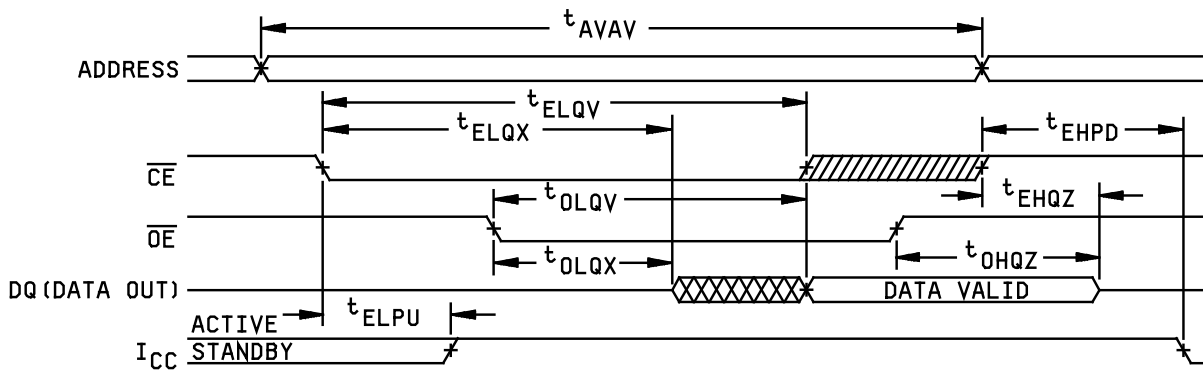
FIGURE 3. AC output loading.

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READ CYCLE 1 (SEE NOTES 1 AND 2)



READ CYCLE 2 (SEE NOTES 1 AND 2)

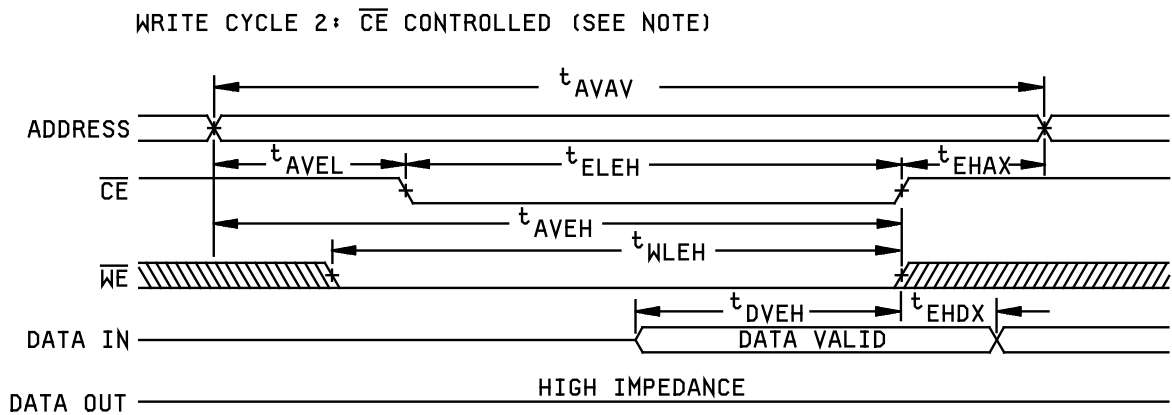
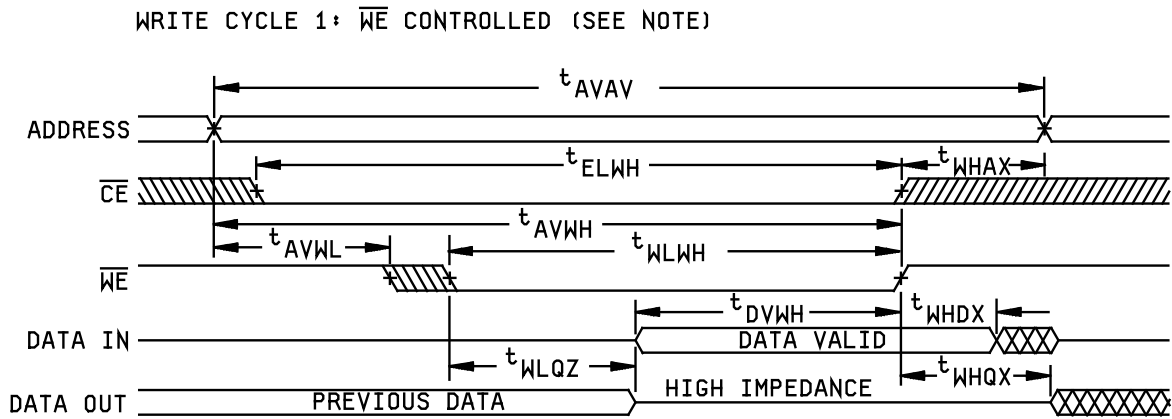


NOTES:

1. For read cycles 1 and 2,  $\overline{WE}$  is high for entire cycle.
2. Device is continuously selected with  $\overline{CE}$  low and  $\overline{OE}$  low.

FIGURE 4. Timing waveforms.

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NOTE:  $\overline{CE}$  or  $\overline{WE}$  must be  $\geq V_{IH}$  during address transitions.

FIGURE 4. Timing waveforms - Continued.

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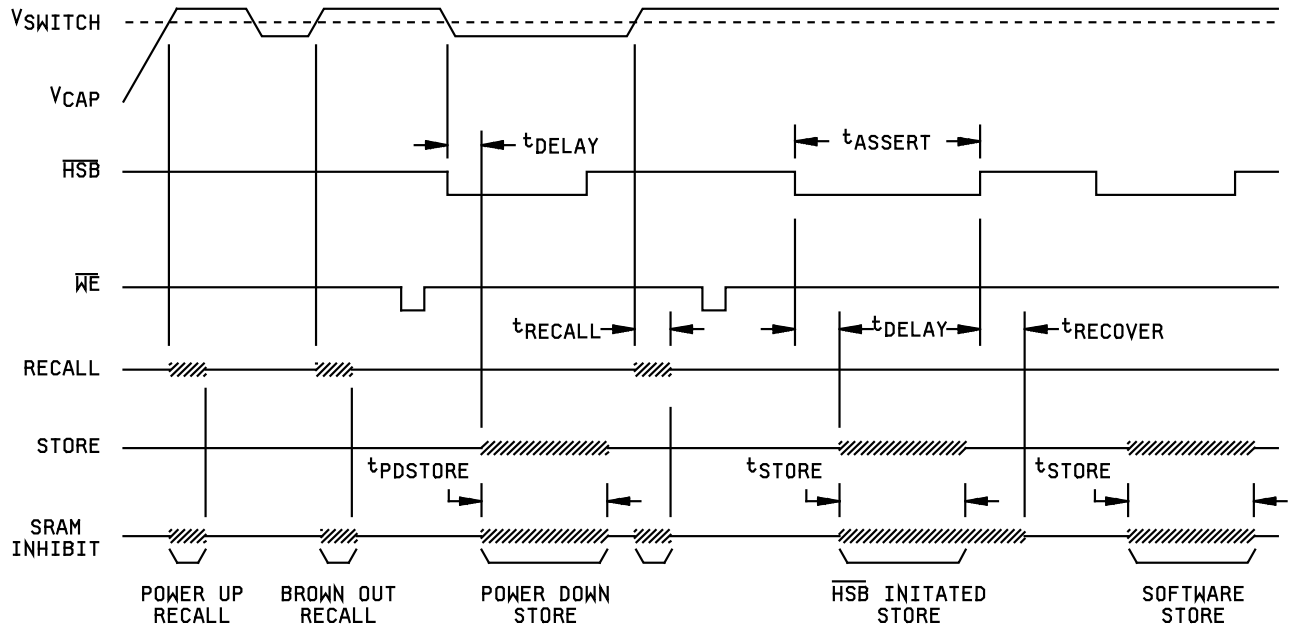
SIZE  
**A**

REVISION LEVEL  
**C**

**5962-94599**

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HARDWARE STORE/RECALL (see note)



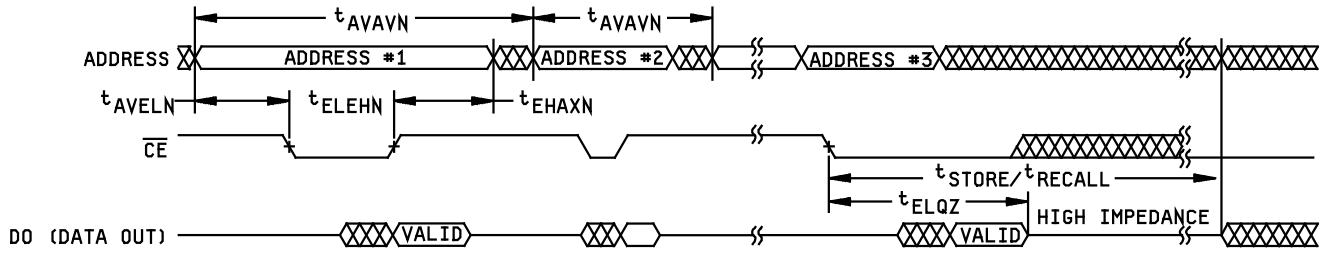
NOTE: RECALL and STORE indicate operations performed within the nvSRAM. These operations are transparent to the user except where SRAM INHIBIT indicates that the SRAM cannot be accessed (outputs are tri-state, inputs are disabled).

FIGURE 4. Timing waveforms - Continued.

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SOFTWARE STORE/RECALL (see notes 1, 2, and 3)



NOTES:

1. If the Chip Enable Pulse Width is less than  $t_{ELQV}$  (see READ CYCLE #2) but greater than or equal to  $t_{ELEHN}$ , then the data may not be valid at the end of the low pulse, however, the STORE or RECALL will still be initiated.
2.  $\overline{WE}$  must be HIGH when  $\overline{CE}$  is LOW during the address sequence in order to initiate a nonvolatile cycle.  $\overline{OE}$  may be either HIGH or LOW throughout.
3.  $\overline{CE}$  must be used to clock in the address sequence for the Software STORE and RECALL cycles.

FIGURE 4. Timing waveforms - Continued.

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TABLE IIA. Electrical test requirements. 1/, 2/, 3/, 4/, 5/, 6/, 7/

Line no.	Test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)	Subgroups (in accordance with MIL-PRF-38535, table III)	
		Device class M	Device class Q	Device class V
1	Interim electrical parameters (see 4.2)		1, 7, 9	1, 7, 9
2	Static burn-in I and II (method 1015)	Not required	Not required	Required
3	Same as line 1			1*, 7* Δ
4	Dynamic burn-in (method 1015)	Required	Required	Required
5	Same as line 1			1*, 7* Δ
6	Final electrical parameters (see 4.2)	1*, 2, 3, 7*, 8A, 8B, 9, 10, 11	1*, 2, 3, 7*, 8A, 8B, 9, 10, 11	1*, 2, 3, 7*, 8A, 8B, 9, 10, 11
7	Group A test requirements (see 4.4)	1, 2, 3, 4**, 7, 8A, 8B, 9, 10, 11	1, 2, 3, 4**, 7, 8A, 8B, 9, 10, 11	1, 2, 3, 4**, 7, 8A, 8B, 9, 10, 11
8	Group C end-point electrical parameters (see 4.4)	2, 3, 7, 8A, 8B	1, 2, 3, 7, 8A, 8B Δ	1, 2, 3, 7, 8A, 8B, 9, 10, 11 Δ
9	Group D end-point electrical parameters (see 4.4)	2, 3, 8A, 8B	2, 3, 8A, 8B	2, 3, 8A, 8B
10	Group E end-point electrical parameters (see 4.4)	1, 7, 9	1, 7, 9	1, 7, 9

1/ Blank spaces indicate tests are not applicable.

2/ Any or all subgroups may be combined when using high-speed testers.

3/ Subgroups 7 and 8 functional tests shall verify the truth table.

4/ \* indicates PDA applies to subgroup 1 and 7.

5/ \*\* see 4.4.1e.

6/ Δ indicates delta limit (see table IIB) shall be required where specified, and the delta values shall be computed with reference to the previous interim electrical parameters (see line 1).

7/ See 4.4.1d.

TABLE IIB. Delta limits at +25°C.

Parameter 1/	Device types
	All
I <sub>CC2</sub> standby	N/A (Class M device)
I <sub>I</sub> , I <sub>O</sub>	N/A (Class M device)

1/ The above parameter shall be recorded before and after the required burn-in and life tests to determine the delta Δ

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4.3 Qualification inspection for device classes Q and V. Qualification inspection for device classes Q and V shall be in accordance with MIL-PRF-38535. Inspections to be performed shall be those specified in MIL-PRF-38535 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

4.4 Conformance inspection. Technology conformance inspection for classes Q and V shall be in accordance with MIL-PRF-38535 including groups A, B, C, D, and E inspections and as specified herein. Quality conformance inspection for device class M shall be in accordance with MIL-PRF-38535, appendix A and as specified herein. Inspections to be performed for device class M shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

4.4.1 Group A inspection.

- a. Tests shall be as specified in table IIA herein.
- b. Subgroups 5 and 6 of table I of method 5005 of MIL-STD-883 shall be omitted.
- c. For device class M, subgroups 7 and 8 tests shall be sufficient to verify the truth table. For device classes Q and V, subgroups 7 and 8 shall include verifying the functionality of the device.
- d. O/V (latch-up) tests shall be measured only for initial qualification and after any design or process changes which may affect the performance of the device. For device class M, procedures and circuits shall be maintained under document revision level control by the manufacturer and shall be made available to the preparing activity or acquiring activity upon request. For device classes Q and V, the procedures and circuits shall be under the control of the device manufacturer's TRB in accordance with MIL-PRF-38535 and shall be made available to the preparing activity or acquiring activity upon request. Testing shall be on all pins, on five devices with zero failures. Latch-up test shall be considered destructive. Information contained in JESD 78 may be used for reference.
- e. Subgroup 4 ( $C_{IN}$  and  $C_{OUT}$  measurements) shall be measured only for initial qualification and after any process or design changes which may affect input or output capacitance. Capacitance shall be measured between the designated terminal and GND at a frequency of 1 MHz. Sample size is 15 devices with no failures, and all input and output terminals tested.

4.4.2 Group C inspection. The group C inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.2.1 Additional criteria for device class M. Steady-state life test conditions, method 1005 of MIL-STD-883:

- a. Test condition D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
- b.  $T_A = +125^{\circ}\text{C}$ , minimum.
- c. Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.4.2.2 Additional criteria for device classes Q and V. The steady-state life test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The test circuit shall be maintained under document revision level control by the device manufacturer's TRB in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.

4.4.3 Group D inspection. The group D inspection end-point electrical parameters shall be as specified in table IIA herein.

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4.4.4 Group E inspection. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein).

- a. End-point electrical parameters shall be as specified in table IIA herein.
- b. For device classes Q and V, the devices or test vehicle shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38535 for the RHA level being tested. For device class M, the devices shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38535, appendix A for the RHA level being tested. All device classes must meet the postirradiation end-point electrical parameter limits as defined in table I at  $T_A = +25^{\circ}\text{C} \pm 5^{\circ}\text{C}$ , after exposure, to the subgroups specified in table IIA herein.

4.5 Delta measurements for device classes Q, and V. Delta measurements, as specified in table IIA, shall be made and recorded before and after the required burn-in screens and steady-state life tests to determine delta compliance. The electrical parameters to be measured, with associated delta limits are listed in table IIB. The device manufacturer may, at his option, either perform delta measurements or within 24 hours after burn-in perform final electrical parameter tests, subgroups 1, 7, and 9.

## 5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

## 6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.1.1 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor prepared specification or drawing.

6.1.2 Substitutability. Device class Q devices will replace device class M devices.

6.2 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.

6.3 Record of users. Military and industrial users should inform DLA Land and Maritime when a system application requires configuration control and which SMD's are applicable to that system. DLA Land and Maritime will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DLA Land and Maritime-VA, telephone (614) 692-8108.

6.4 Comments. Comments on this drawing should be directed to DLA Land and Maritime-VA , Columbus, Ohio 43218-3990, or telephone (614) 692-0540


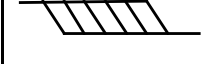
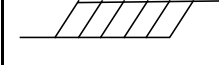

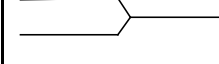
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6.5 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535, MIL-HDBK-1331 and as follows:

C <sub>IN</sub> .....	Input terminal capacitance.
C <sub>OUT</sub> .....	Output terminal capacitance.
GND .....	Ground zero voltage potential.
I <sub>CC</sub> .....	Supply current.
I <sub>IH</sub> .....	Input high current.
I <sub>ILT</sub> .....	Input low current.
T <sub>C</sub> .....	Case temperature.
T <sub>A</sub> .....	Ambient temperature
V <sub>CC</sub> .....	Ground zero voltage potential.
O/V .....	Latch-up over-voltage
<u>HSB</u> .....	Hardware store/busy
VCAP .....	Capacitor voltage

6.5.1 Timing limits. The table of timing values shows either a minimum or a maximum limit for each parameter. Input requirements are specified from the external system point of view. Thus, address setup time is shown as a minimum since the system must supply at least that much time (even though most devices do not require it). On the other hand, responses from the memory are specified from the device point of view. Thus, the access time is shown as a maximum since the device never provides data later than that time.

6.5.2 Waveforms.

Waveform symbol	Input	Output
	MUST BE VALID	WILL BE VALID
	CHANGE FROM H TO L	WILL CHANGE FROM H TO L
	CHANGE FROM L TO H	WILL CHANGE FROM L TO H
	DON'T CARE ANY CHANGE PERMITTED	CHANGING STATE UNKNOWN
		HIGH IMPEDANCE

6.6 Sources of supply.

6.6.1 Sources of supply for device classes Q and V. Sources of supply for device classes Q and V are listed in QML-38535 and MIL-HDBK-103. The vendors listed in QML-38535 and MIL-HDBK-103 have submitted a certificate of compliance (see 3.6 herein) to DLA Land and Maritime-VA and have agreed to this drawing.

6.6.2 Approved sources of supply for device class M. Approved sources of supply for class M are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DLA Land and Maritime-VA.

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## APPENDIX A

APPENDIX A forms a part of SMD 5962-94599

### FUNCTIONAL ALGORITHMS

#### A.1 SCOPE

A.1.1 Scope. Functional algorithms are test patterns which define the exact sequence of events used to verify proper operation of a random access memory (RAM). Each algorithm serves a specific purpose for the testing of the device. It is understood that all manufacturers do not have the same test equipment; therefore, it becomes the responsibility of each manufacturer to guarantee that the test patterns described herein are followed as closely as possible, or equivalent patterns be used that serve the same purpose. Each manufacturer should demonstrate that this condition will be met. Algorithms shall be applied to the device in a topologically pure fashion. This appendix is a mandatory part of the specification. The information contained herein is intended for compliance.

A.2 APPLICABLE DOCUMENTS. This section is not applicable to this appendix.

#### A.3 ALGORITHMS

##### A.3.1 Algorithm A (pattern 1).

###### A.3.1.1 Checkerboard, checkerboard-bar.

- Step 1. Load memory with a checkerboard data pattern by incrementing from location 0 to maximum.
- Step 2. Read memory, verifying the output checkerboard pattern by incrementing from location 0 to maximum.
- Step 3. Load memory with a checkerboard-bar pattern by incrementing from location 0 to maximum.
- Step 4. Read memory, verifying the output checkerboard-bar pattern by incrementing from location 0 to maximum.

##### A.3.2 Algorithm B (pattern 2).

###### A.3.2.1 March.

- Step 1. Load memory with background data, incrementing from minimum to maximum address locations (all "0's").
- Step 2. Read data in location 0.
- Step 3. Write complement data to location 0.
- Step 4. Read complement data in location 0.
- Step 5. Repeat steps 2 through 4 incrementing X-fast sequentially for each location in the array.
- Step 6. Read complement data in maximum address location.
- Step 7. Write data to maximum address location.
- Step 8. Read data in maximum address location.
- Step 9. Repeat steps 6 through 8 decrementing X-fast sequentially for each location in the array.
- Step 10. Read data in location 0.
- Step 11. Write complement data to location 0.
- Step 12. Read complement data in location 0.
- Step 13. Repeat steps 10 through 12 decrementing X-fast sequentially for each location in the array.
- Step 14. Read complement data in maximum address location.
- Step 15. Write data to maximum address location.
- Step 16. Read data in maximum address location.
- Step 17. Repeat steps 14 through 16 incrementing X-fast sequentially for each location in the array.
- Step 18. Read background data from memory, decrementing X-fast from maximum to minimum address locations.

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APPENDIX A – continued.

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A.3.3 Algorithm C (pattern 3).

A.3.3.1 XY March.

- Step 1. Load memory with background data, incrementing from minimum to maximum address locations (all "0's").
- Step 2. Read data in location 0.
- Step 3. Write complement data to location 0.
- Step 4. Read complement data in location 0.
- Step 5. Repeat steps 2 through 4 incrementing Y-fast sequentially for each location in the array.
- Step 6. Read complement data in maximum address location.
- Step 7. Write data to maximum address location.
- Step 8. Read data in maximum address location.
- Step 9. Repeat steps 6 through 8 decrementing X-fast sequentially for each location in the array.
- Step 10. Read data in location 0.
- Step 11. Write complement data to location 0.
- Step 12. Read complement data in location 0.
- Step 13. Repeat steps 10 through 12 decrementing Y-fast sequentially for each location in the array.
- Step 14. Read complement data in maximum address location.
- Step 15. Write data to maximum address location.
- Step 16. Read data in maximum address location.
- Step 17. Repeat steps 14 through 16 incrementing X-fast sequentially for each location in the array.
- Step 18. Read background data from memory, decrementing Y-fast from maximum to minimum address locations.

A.3.4 Algorithm D (pattern 4).

A.3.4.1 CEDES - CE deselect checkerboard, checkerboard-bar.

- Step 1. Load memory with a checkerboard data pattern by incrementing from location 0 to maximum.
- Step 2. Deselect device, attempt to load memory with checkerboard-bar data pattern by incrementing from location 0 to maximum.
- Step 3. Read memory, verifying the output checkerboard pattern by incrementing from location 0 to maximum.
- Step 4. Load memory with a checkerboard-bar pattern by incrementing from location 0 to maximum.
- Step 5. Deselect device, attempt to load memory with checkerboard data pattern by incrementing from location 0 to maximum.
- Step 6. Read memory, verifying the output checkerboard-bar pattern by incrementing from location 0 to maximum.

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STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 14-08-11

Approved sources of supply for SMD 5962-94599 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 during the next revision. MIL-HDBK-103 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DLA Land and Maritime-VA. This information bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535. DLA Land and Maritime maintains an online database of all current sources of supply at <http://www.landandmaritime.dla.mil/Programs/Smcr/>.

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>
5962-9459901MXA	65786	STK12C68-5K55M
5962-9459901MXC	<u>3/</u>	STK12C68-5C55M
5962-9459901MYA	<u>3/</u>	STK12C68-5L55M
5962-9459902MXA	<u>3/</u>	STK12C68-5K45M
5962-9459902MXC	<u>3/</u>	STK12C68-5C45M
5962-9459902MYA	<u>3/</u>	STK12C68-5L45M
5962-9459903MXA	65786	STK12C68-5K35M
5962-9459903MXC	<u>3/</u>	STK12C68-5C35M
5962-9459903MYA	65786	STK12C68-5L35M

1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.

2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

3/ No longer available from an approved source. The last known source is listed below.

Vendor CAGE  
number

65786

Vendor name  
and address

Cypress Semiconductor  
198 Champion Court  
San Jose, CA 95134-1709

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.